

P-Channel Enhancement Mode MOSFET

Features

Pin Description

· -20V/-2.8A

$$R_{DS(ON)} = 56m\Omega \text{ (typ.)} @ V_{GS} = -4.5V$$

 $R_{DS(ON)} = 85m\Omega \text{ (typ.)} @ V_{GS} = -2.5V$
 $R_{DS(ON)} = 106m\Omega \text{ (typ.)} @ V_{GS} = -1.8V$

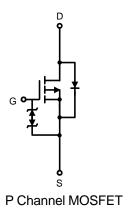
- Super High Dense Cell Design
- · Reliable and Rugged



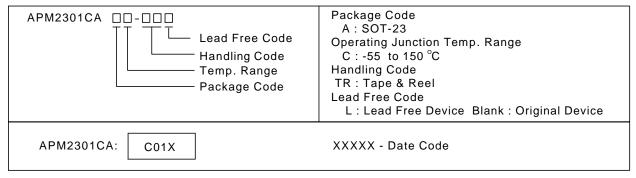
SOT-23

Applications

Power Management in Notebook Computer,
 Portable Equipment and Battery Powered
 Systems.



Ordering and Marking Information



Note: ANPEC lead-free products contain molding compounds/die attach materials and 100% matte tin plate termination finish; which are fully compliant with RoHS and compatible with both SnPb and lead-free soldiering operations. ANPEC lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J STD-020C for MSL classification at lead-free peak reflow temperature.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.



Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

Symbol	Parameter		Rating	Unit	
V_{DSS}	Drain-Source Voltage		-20	V	
V_{GSS}	Gate-Source Voltage		±12	V	
I _D *	Continuous Drain Current				
I _{DM} *	300μs Pulsed Drain Current	V _{GS} =-4.5V	-12	Α	
l _s *	Diode Continuous Forward Current	-1.3	Α		
T_J	Maximum Junction Temperature	150	°C		
T _{STG}	Storage Temperature Range	-55 to 150	O		
P _D *	Maximum Daviar Dissination	T _A =25°C	0.83	W	
L LD	Maximum Power Dissipation	T _A =100°C	0.3	VV	
R _{θJA} *	Thermal Resistance-Junction to Amb	pient	150	°C/W	

Notes: *Surface Mounted on $1in^2$ pad area, $t \le 10sec$.

Electrical Characteristics $(T_A = 25^{\circ}C \text{ Unless Otherwise Noted})$

Symbol	Doromotor	Took Condition	APM2301CA			l ln:4	
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit	
Static Ch	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} =0V, I_{DS} =250 μ A	-20			V	
	Zava Cata Valtaga Duais Current	V _{DS} =-16V, V _{GS} =0V			-1		
I _{DSS}	Zero Gate Voltage Drain Current	T _J =85°C			-30	μΑ	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{DS} = -250 \mu A$	-0.5	-0.75	-1	V	
I _{GSS}	Gate Leakage Current	V _{GS} =±12V, V _{DS} =0V			±10	μΑ	
		V _{GS} =-4.5V, I _{DS} =-2.8A		56	70		
R _{DS(ON)} a	Drain-Source On-State Resistance	V _{GS} =-2.5V, I _{DS} =-2A		85	115	mΩ	
		V _{GS} =-1.8V, I _{DS} =-1A		106	165		
V _{SD} ^a	Diode Forward Voltage	I _{SD} =-1.3A, V _{GS} =0V		-0.75	-1.3	V	
Gate Cha	arge Characteristics ^b						
Qg	Total Gate Charge	101/11/14/51/		7	10	nC	
Q_{gs}	Gate-Source Charge	V _{DS} =-10V, V _{GS} =-4.5V, I _{DS} =-2.8A		1.9			
Q_{gd}	Gate-Drain Charge	טיין – 2.0/ נ		1.9			



Electrical Characteristics (Cont.) $(T_A = 25^{\circ}C \text{ Unless Otherwise Noted})$

Cumbal	Davamatar	Took Condition	APM2301CA			11:4	
Symbol Parameter		Test Condition	Min.	Тур.	Max.	Unit	
Dynamic	Dynamic Characteristics ^b						
C _{iss}	Input Capacitance	V _{GS} =0V,		580			
C _{oss}	Output Capacitance	V _{DS} =-10V,		100		pF	
C_{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz		75			
t _{d(ON)}	Turn-on Delay Time	V 40V B 400		4	7		
t _r	Turn-on Rise Time	V_{DD} =-10V, R _L =10 Ω , I_{DS} =1A, V_{GEN} =-4.5V,		13	23	no	
t _{d(OFF)}	Turn-off Delay Time	$R_G=6\Omega$		35	63	ns	
t _f	Turn-off Fall Time			20	36		
t _{rr}	Reverse Recovery Time	I _{SD} =-2.8A,		20		ns	
Q_{rr}	Reverse Recovery Charge	dl _{SD} /dt =100A/µs		7		nC	

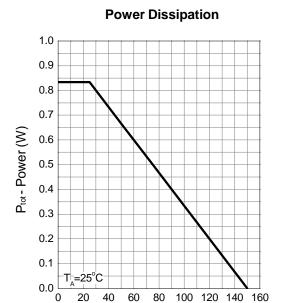
Notes:

a : Pulse test ; pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$.

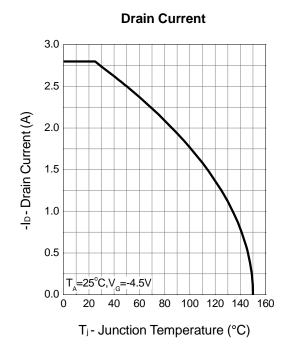
b : Guaranteed by design, not subject to production testing.



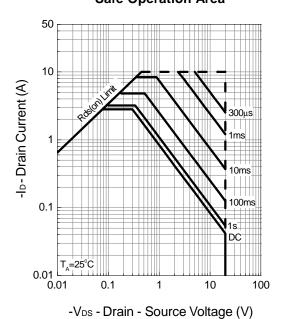
Typical Characteristics



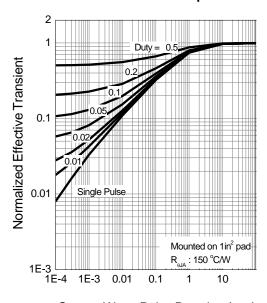
T_j- Junction Temperature (°C)



Safe Operation Area



Thermal Transient Impedance

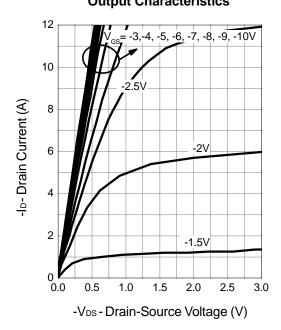


Square Wave Pulse Duration (sec)

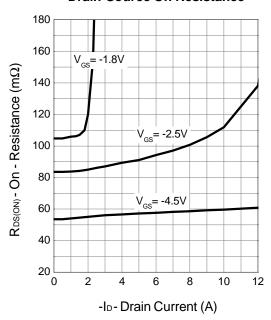


Typical Characteristics (Cont.)

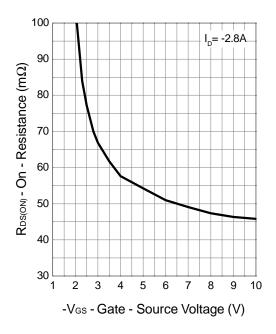
Output Characteristics



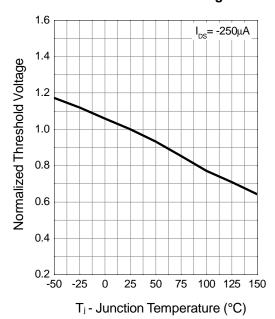
Drain-Source On Resistance



Drain-Source On Resistance



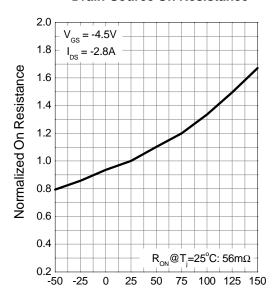
Gate Threshold Voltage





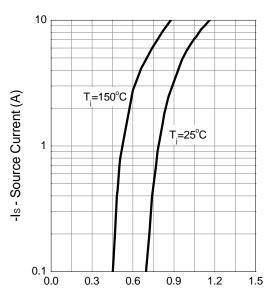
Typical Characteristics (Cont.)

Drain-Source On Resistance



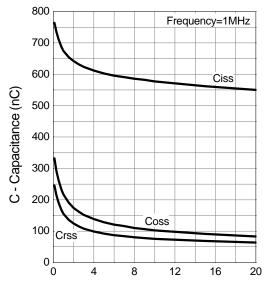
T_j- Junction Temperature (°C)

Source-Drain Diode Forward



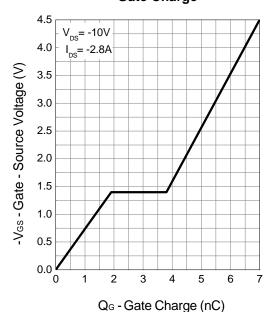
-Vsp - Source - Drain Voltage (V)

Capacitance



-VDS - Drain - Source Voltage (V)

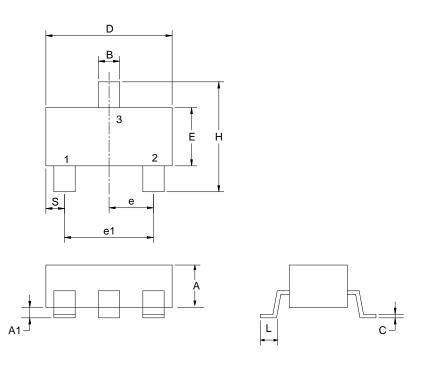
Gate Charge





Packaging Information

SOT-23



Dim	Parar	neter	Inches		
ווווט	Min.	Max.	Min.	Max.	
А	1.00	1.30	0.039	0.051	
A1	0.00	0.10	0.000	0.004	
В	0.35	0.51	0.014	0.020	
С	0.10	0.25	0.004	0.010	
D	2.70	3.10	0.106	0.122	
Е	1.40	1.80	0.055	0.071	
e1	1.90	90 TYP 0.075 TY		ГҮР	
Н	2.40	3.00	0.094	0.118	
L	0.37		0.015		

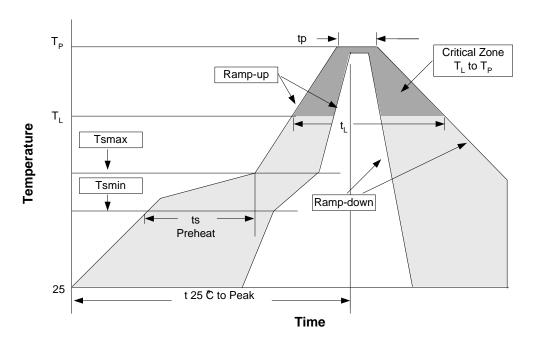
Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb,100%Sn).
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.



Reflow Condition

(IR/Convection or VPR Reflow)



Reflow Condition

Profile Feature	Sn-Pb Eutec	tic Assembly	Pb-Free Assembly		
Profile readure	Large Body	Small Body	Large Body	Small Body	
Average ramp-up rate(T _L to T _P)	3°C/sec	ond max.	3°C/second max.		
Preheat -Temperature Min (Tsmin) -Temperature Max (Tsmax) -Time (min to max) (ts)	100°C 150°C 60-120 seconds		150°C 200°C 60-180 seconds		
Tsmax to T _L -Ramp-up Rate			3°C/second max		
Time maintained above: -Temperature (T _L) -Time (t _L)	183°C 60-150 seconds		217°C 60-150 seconds		
Peak Temperature (Tp)	225 +0/-5°C	240 +0/-5°C	245 +0/-5°C	250 +0/-5°C	
Time within 5°C of actual Peak Temperature (tp)	10-30 seconds	10-30 seconds	10-30 seconds	20-40 seconds	
Ramp-down Rate	6°C/second max. 6°C		6°C/sec	/second max.	
Time 25°C to Peak Temperature	6 minutes ma		8 minutes max.		

Notes: All temperatures refer to topside of the package .Measured on the body surface.



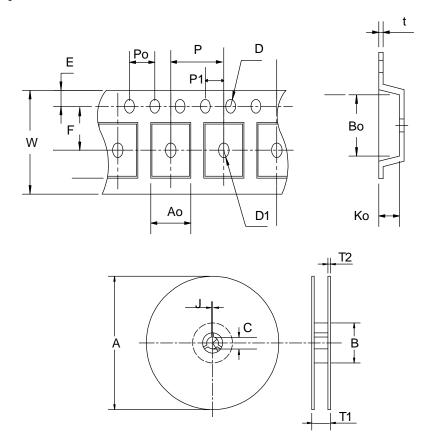
Reflow Condition

pkg. thickness ³ 2.5mm and all bags	pkg. thickness < 2.5mm and pkg. volume ³ 350mm ³	pkg. thickness < 2.5mm and pkg. volume < 350mm ³
Convection 220 +5/-0°C		Convection 235 +5/-0°C
VPR 215-219°C		VPR 235 +5/-0°C
IR/Convection 220 +5/-0°C		IR/Convection 220 +5/-0°C

Reliability test program

Test Item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
тѕт	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

Carrier Tape & Reel Dimensions





Carrier Tape & Reel Dimensions (Cont.)

Application	Α	В	С	J	T1	T2	W	Р	Е
	178±1	60±1.0	12.0	2.5±0.15	9.0±0.5	1.4	8.0±0.3	4.0	1.75
SOT-23	F	D	D1	Po	P1	Ao	Во	Ko	t
	3.5±0.05	1.5±0.1	φ0.1MIN	4.0	2.0±0.05	3.1	3.0	1.3	0.2±0.03

Cover Tape Dimensions

Application	Carrier Width	Cover Tape Width	Devices Per Reel
SOT-23	8	5.3	3000

Customer Service

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